Search Notes				

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/693,544	SUGIYAMA ET AL.	
Examiner	Art Unit	
Thanh X. Luu	2878	

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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